

Notice of References Cited	Application/Control No. 09/510,074	Applicant(s)/Patent Under Reexamination AOKI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,400,929	06-2002	Ue et al.	455/69
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	K	US-			
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,400,929	06-2002	Ue et al.	455/69
	B	US-5,267,261	11-1993	Blakeney et al.	370/332
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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